

IRF7905PbF

HEXFET® Power MOSFET

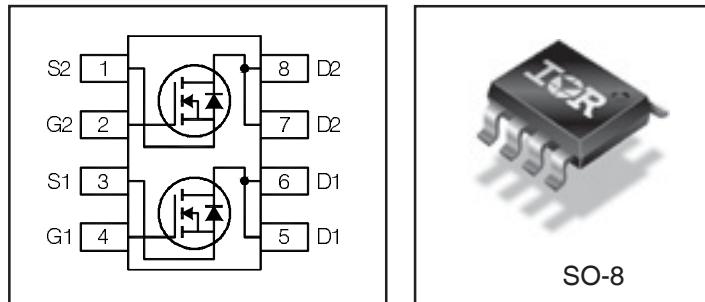
Applications

- Dual SO-8 MOSFET for POL Converters in Notebook Computers, Servers, Graphics Cards, Game Consoles and Set-Top Box

V_{DSS}	R_{DS(on)} max	I_D
30V	Q1 21.8mΩ@V_{GS} = 10V	7.8A
	Q2 17.1mΩ@V_{GS} = 10V	8.9A

Benefits

- Very Low R_{DS(on)} at 4.5V V_{GS}
- Low Gate Charge
- Fully Characterized Avalanche Voltage and Current
- 20V V_{GS} Max. Gate Rating
- Improved Body Diode Reverse Recovery
- 100% Tested for R_G
- Lead-Free



Absolute Maximum Ratings

	Parameter	Q1 Max.	Q2 Max.	Units
V _{DS}	Drain-to-Source Voltage	30		V
V _{GS}	Gate-to-Source Voltage		± 20	
I _D @ T _A = 25°C	Continuous Drain Current, V _{GS} @ 10V	7.8	8.9	
I _D @ T _A = 70°C	Continuous Drain Current, V _{GS} @ 10V	6.2	7.1	A
I _{DM}	Pulsed Drain Current ①	62	71	
P _D @ T _A = 25°C	Power Dissipation	2.0	2.0	W
P _D @ T _A = 70°C	Power Dissipation	1.3	1.3	
	Linear Derating Factor	0.016	0.016	W/°C
T _J	Operating Junction and Storage Temperature Range	-55 to + 150		°C

Thermal Resistance

	Parameter	Q1 Max.	Q2 Max.	Units
R _{θJL}	Junction-to-Drain Lead ⑤	42	42	°C/W
R _{θJA}	Junction-to-Ambient ④⑤	62.5	62.5	

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Static @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

International
Rectifier

	Parameter		Min.	Typ.	Max.	Units	Conditions
V_{BDS}	Drain-to-Source Breakdown Voltage	Q1&Q2	30	—	—	V	$V_{GS} = 0V, I_D = 250\mu\text{A}$
$\Delta V_{BDS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	Q1	—	0.024	—	V/ $^\circ\text{C}$	Reference to $25^\circ\text{C}, I_D = 1\text{mA}$
		Q2	—	0.024	—		
$R_{DS(on)}$	Static Drain-to-Source On-Resistance	Q1	—	17.4	21.8	m Ω	$V_{GS} = 10V, I_D = 7.8\text{A}$ ③
		—	—	23.4	29.3		$V_{GS} = 4.5V, I_D = 6.2\text{A}$ ③
		Q2	—	13.7	17.1		$V_{GS} = 10V, I_D = 8.9\text{A}$ ③
		—	—	17.1	21.3		$V_{GS} = 4.5V, I_D = 7.1\text{A}$ ③
$V_{GS(th)}$	Gate Threshold Voltage	Q1&Q2	1.35	1.8	2.25	V	$V_{DS} = V_{GS}, I_D = 25\mu\text{A}$
$\Delta V_{GS(th)}/\Delta T_J$	Gate Threshold Voltage Coefficient	Q1	—	-5.0	—	mV/ $^\circ\text{C}$	
		Q2	—	-5.0	—		
I_{DSS}	Drain-to-Source Leakage Current	Q1&Q2	—	—	1.0	μA	$V_{DS} = 24V, V_{GS} = 0V$
		Q1&Q2	—	—	150		$V_{DS} = 24V, V_{GS} = 0V, T_J = 125^\circ\text{C}$
I_{GSS}	Gate-to-Source Forward Leakage	Q1&Q2	—	—	100	nA	$V_{GS} = 20V$
	Gate-to-Source Reverse Leakage	Q1&Q2	—	—	-100		$V_{GS} = -20V$
g_{fs}	Forward Transconductance	Q1	15	—	—	S	$V_{DS} = 15V, I_D = 6.2\text{A}$
		Q2	18	—	—		$V_{DS} = 15V, I_D = 7.1\text{A}$
Q_g	Total Gate Charge	Q1	—	4.6	6.9	nC	
		Q2	—	6.9	10		
Q_{gs1}	Pre-Vth Gate-to-Source Charge	Q1	—	0.9	—		Q1 $V_{DS} = 15V$ $V_{GS} = 4.5V, I_D = 6.2\text{A}$
		Q2	—	1.5	—		
Q_{gs2}	Post-Vth Gate-to-Source Charge	Q1	—	0.6	—		Q2 $V_{DS} = 15V$ $V_{GS} = 4.5V, I_D = 7.1\text{A}$
		Q2	—	0.8	—		
Q_{gd}	Gate-to-Drain Charge	Q1	—	1.7	—		
		Q2	—	2.5	—		
Q_{godr}	Gate Charge Overdrive	Q1	—	1.4	—		
		Q2	—	2.1	—		
Q_{sw}	Switch Charge ($Q_{gs2} + Q_{gd}$)	Q1	—	2.3	—		
		Q2	—	3.3	—		
Q_{oss}	Output Charge	Q1	—	2.9	—	nC	$V_{DS} = 16V, V_{GS} = 0V$
		Q2	—	4.5	—		
R_G	Gate Resistance	Q1	—	3.1	4.9	Ω	
		Q2	—	3.1	4.9		
$t_{d(on)}$	Turn-On Delay Time	Q1	—	5.2	—	ns	Q1 $V_{DD} = 15V, V_{GS} = 4.5V$ $I_D = 6.2\text{A}$
		Q2	—	6.2	—		
t_r	Rise Time	Q1	—	8.3	—		Q2 $V_{DD} = 15V, V_{GS} = 4.5V$ $I_D = 7.1\text{A}$
		Q2	—	9.3	—		Clamped Inductive Load
$t_{d(off)}$	Turn-Off Delay Time	Q1	—	6.9	—		
		Q2	—	8.1	—		
t_f	Fall Time	Q1	—	3.4	—		
		Q2	—	3.4	—		
C_{iss}	Input Capacitance	Q1	—	600	—	pF	$V_{GS} = 0V$
		Q2	—	910	—		$V_{DS} = 15V$
C_{oss}	Output Capacitance	Q1	—	130	—		$f = 1.0\text{MHz}$
		Q2	—	190	—		
C_{rss}	Reverse Transfer Capacitance	Q1	—	78	—		
		Q2	—	95	—		

Avalanche Characteristics

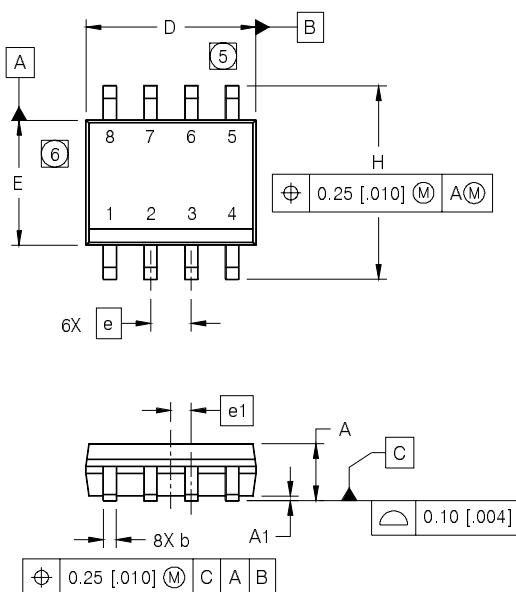
	Parameter		Typ.	Q1 Max.	Q2 Max.	Units
E_{AS}	Single Pulse Avalanche Energy ③	—	—	12	18	mJ
I_{AR}	Avalanche Current ①	—	—	6.2	7.1	A

Diode Characteristics

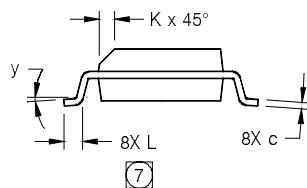
	Parameter		Min.	Typ.	Max.	Units	Conditions	
I_S	Continuous Source Current (Body Diode)	Q1	—	—	2.8	A	MOSFET symbol showing the integral reverse p-n junction diode.	
		Q2	—	—	2.8			
I_{SM}	Pulsed Source Current (Body Diode) ①	Q1	—	—	62	A		
		Q2	—	—	71			
V_{SD}	Diode Forward Voltage	Q1	—	—	1.0	V	$T_J = 25^\circ\text{C}, I_S = 6.1\text{A}, V_{GS} = 0V$ ③	
		Q2	—	—	1.0		$T_J = 25^\circ\text{C}, I_S = 7.1\text{A}, V_{GS} = 0V$ ③	
t_{rr}	Reverse Recovery Time	Q1	—	10	15	ns	$T_J = 25^\circ\text{C}, I_F = 6.2\text{A}, V_{DD} = 15V, di/dt = 100\text{A}/\mu\text{s}$ ③	
		Q2	—	13	20		$T_J = 25^\circ\text{C}, I_F = 7.1\text{A}, V_{DD} = 15V, di/dt = 100\text{A}/\mu\text{s}$ ③	
Q_{rr}	Reverse Recovery Charge	Q1	—	2.5	3.8	nC	$T_J = 25^\circ\text{C}, I_F = 7.1\text{A}, V_{DD} = 15V, di/dt = 100\text{A}/\mu\text{s}$ ③	
		Q2	—	4.0	6.0			

SO-8 Package Outline (Mosfet & Fetky)

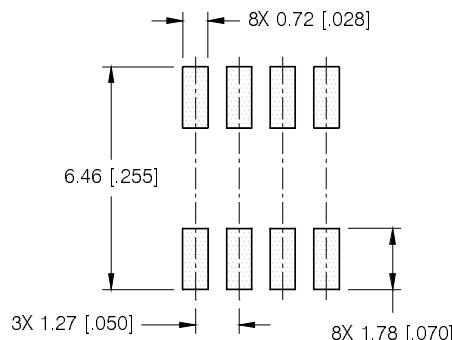
Dimensions are shown in millimeters (inches)



DIM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	.0532	.0688	1.35	1.75
A1	.0040	.0098	0.10	0.25
b	.013	.020	0.33	0.51
c	.0075	.0098	0.19	0.25
D	.189	.1968	4.80	5.00
E	.1497	.1574	3.80	4.00
e	.050	BASIC	1.27	BASIC
e1	.025	BASIC	0.635	BASIC
H	.2284	.2440	5.80	6.20
K	.0099	.0196	0.25	0.50
L	.016	.050	0.40	1.27
y	0°	8°	0°	8°

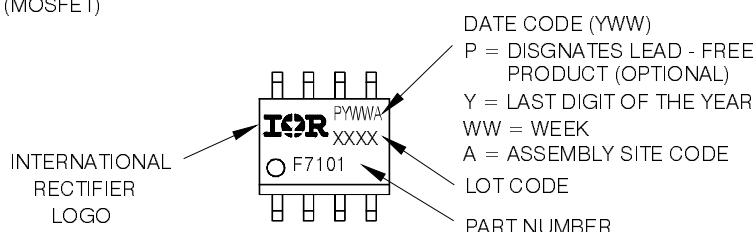


FOOTPRINT



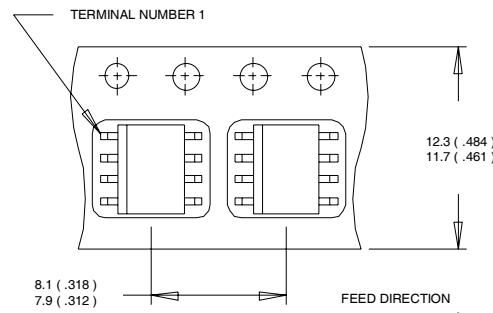
SO-8 Part Marking Information

EXAMPLE: THIS IS AN IRF7101 (MOSFET)



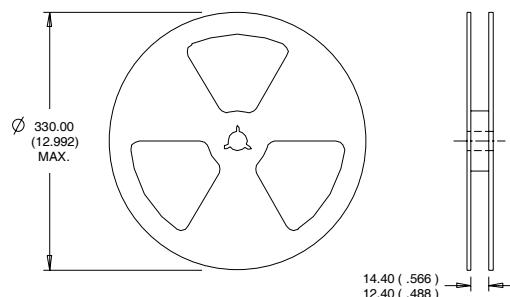
SO-8 Tape and Reel

Dimensions are shown in millimeters (inches)



NOTES:

1. CONTROLLING DIMENSION : MILLIMETER.
2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS(INCHES).
3. OUTLINE CONFORMS TO EIA-481 & EIA-541.



NOTES :

1. CONTROLLING DIMENSION : MILLIMETER.
2. OUTLINE CONFORMS TO EIA-481 & EIA-541.

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature.
- ② Starting $T_J = 25^\circ\text{C}$, Q1: $L = 0.62\text{mH}$
 $R_G = 25\Omega$, $I_{AS} = 6.2\text{A}$; Q2: $L = 0.72\text{mH}$
 $R_G = 25\Omega$, $I_{AS} = 7.1\text{A}$.
- ③ Pulse width $\leq 400\mu\text{s}$; duty cycle $\leq 2\%$.
- ④ When mounted on 1 inch square copper board.
- ⑤ R_θ is measured at T_J approximately 90°C .

Data and specifications subject to change without notice.
 This product has been designed and qualified for the Consumer market.

International
IR Rectifier